

**Search Notes**

Application/Control No.

10/065,171

Examiner

Cheukfan Lee

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

2625

**SEARCHED**

Class	Subclass	Date	Examiner
358	497,494, 474,471	7/18/2006	C.L.
	400,401		
	483,482		
	487,296		
	505,506		
	512-514		
	501,500		
250	239		
	234-236		
	216,208.1		
399	211,212		
355	40,41		
382	312		
	318,319		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
358	471,474	7/18/2006	C.L.
	483		
	497		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search: terms include: (V adj shape\$2) with support\$3 with ((guid\$3 adj (shaft rod)) shaft	7/18/2006	C.L.
Search terms (cont.): (scanner ((scan\$5 read\$3) near3 (original document manuscript object draft))),		
Search terms (cont.): (CCD (charge\$2 adj couple\$2)) ((scan\$5 read\$3) adj (module unit))		
Search terms (cont.): (CIS (contact adj2 image adj2 sensor))		
Inventor search		